

Notice of References Cited		Application/Control No. 10/663,020	Applicant(s)/Patent Under Reexamination CHASE ET AL.	
		Examiner Magid Y. Dimyan	Art Unit 2825	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,608,494 B1	08-2003	Bruce et al.	324/752
*	B	US-6,650,768 B1	11-2003	Evans et al.	382/145
*	C	US-5,940,545	08-1999	Kash et al.	382/312
*	D	US-5,825,191	10-1998	Niijima et al.	324/751
*	E	US-5,682,104	10-1997	Shido	324/751
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Howard, R.E. et al., "Single Electron Switching Events in Nanometer-Scale Si MOSFET's", IEEE Transactions on Electron Devices, Vol. ED-32, No. 9, Sept. 1985, pp. 1669-1674.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.